NMP (1-Methyl-2-pyrrolidinone)
ALEG®

Positive Photoresist Stripper

Material No.: 6397-05
Batch No.: 0000008774
Manufactured Date: 2012/06/25
Retest Date: 2017/06/24

Certificate of Analysis

Test	Specification	Result
Assay (C_5H_9NO)	>= 99.5 %	100.0
Color (APHA)	<= 20	10
Water (H_2O)(by Karl Fischer titrn)	<= 0.05 %	0.03
Free Amines (as CH_3NH_2)	<= 50 ppm	20
Chloride (Cl)	<= 0.5 ppm	< 0.5
Phosphate (PO_4)	<= 1 ppm	< 1
Trace Impurities - Aluminum (Al)	<= 100.0 ppb	< 0.5
Arsenic and Antimony (as As)	<= 100 ppb	< 10
Trace Impurities - Barium (Ba)	<= 100.0 ppb	< 0.5
Trace Impurities - Boron (B)	<= 100.0 ppb	< 2.0
Trace Impurities - Calcium (Ca)	<= 300.0 ppb	3.0
Trace Impurities - Chromium (Cr)	<= 100.0 ppb	< 1.0
Trace Impurities - Cobalt (Co)	<= 100.0 ppb	< 1.0
Trace Impurities - Copper (Cu)	<= 100.0 ppb	< 0.5
Trace Impurities - Gold (Au)	<= 100.0 ppb	2.0
Trace Impurities - Iron (Fe)	<= 100.0 ppb	< 1.0
Trace Impurities - Lead (Pb)	<= 100.0 ppb	< 3.0
Trace Impurities - Lithium (Li)	<= 100.0 ppb	< 0.5
Trace Impurities - Magnesium (Mg)	<= 100.0 ppb	< 0.5
Trace Impurities - Manganese (Mn)	<= 100.0 ppb	< 1.0
Trace Impurities - Nickel (Ni)	<= 100.0 ppb	< 1.0
Trace Impurities - Potassium (K)	<= 100.0 ppb	< 4.0
Trace Impurities - Silver (Ag)	<= 100.0 ppb	< 1.0
Trace Impurities - Sodium (Na)	<= 300.0 ppb	< 1.0

Test	Specification	Result
Trace Impurities – Strontium (Sr)	<= 100.0 ppb	< 0.5
Trace Impurities – Tin (Sn)	<= 100.0 ppb	< 2.0
Trace Impurities – Titanium (Ti)	<= 100.0 ppb	< 1.0
Trace Impurities – Vanadium (V)	<= 100.0 ppb	< 0.5
Trace Impurities – Zinc (Zn)	<= 100.0 ppb	< 1.0
Particle Count - 1.0 µm and greater (Rion KS 42AF)	<= 10 par/ml	1

For Microelectronic Use

Country of Origin:	US
Packaging Site:	Phillipsburg Mfg Ctr & DC

ISO

Phillipsburg, NJ 9001.2008, 14001.2004
Paris, KY 9001.2008
Mexico city, Mexico 9001.2008
Deventer, The Netherlands 9001.2008, 14001.2004
Selangor, Malaysia 9001.2008
Panoli, India 9001.2008
Gliwice, Poland 9001.2008,17025.2005

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